

## Patterning of Lactoferrin Using Functional SAMs of Iron Complexes

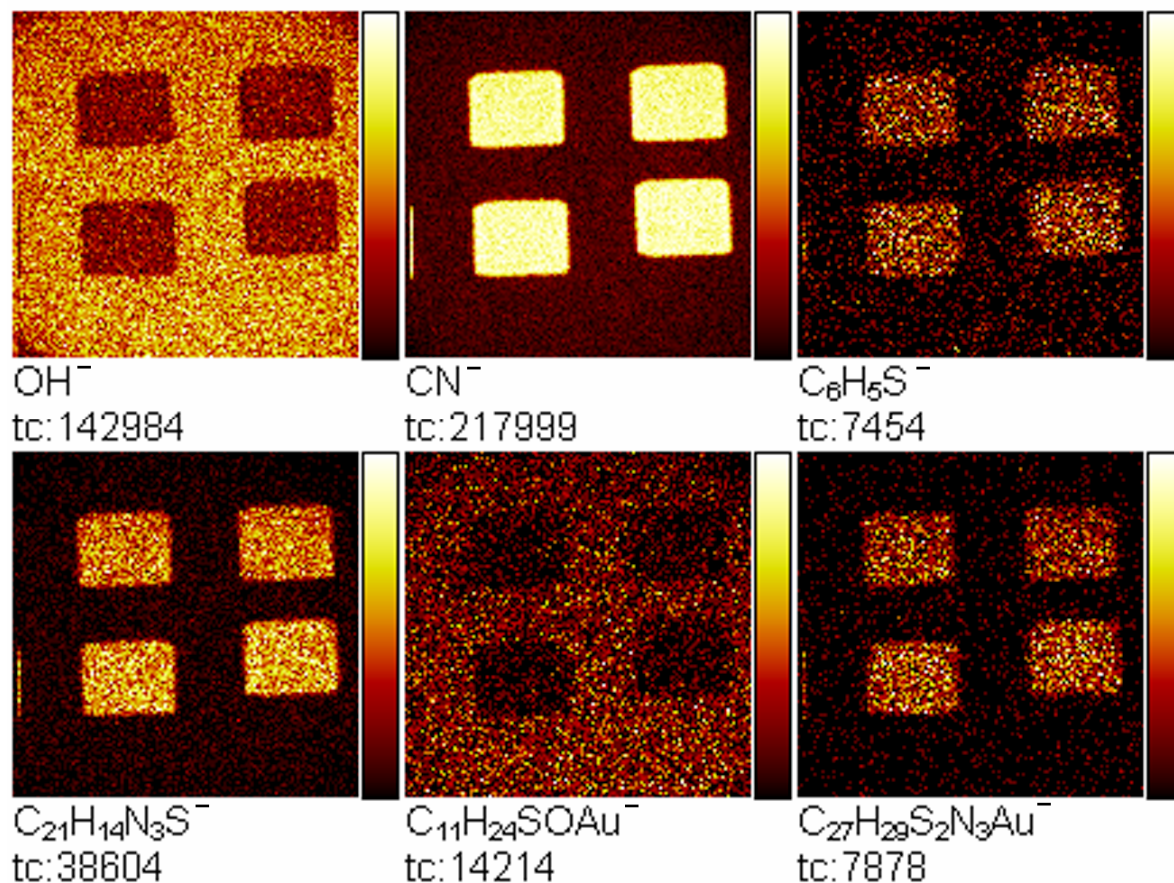
by

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Field of view: 500.0 × 500.0 μm<sup>2</sup>

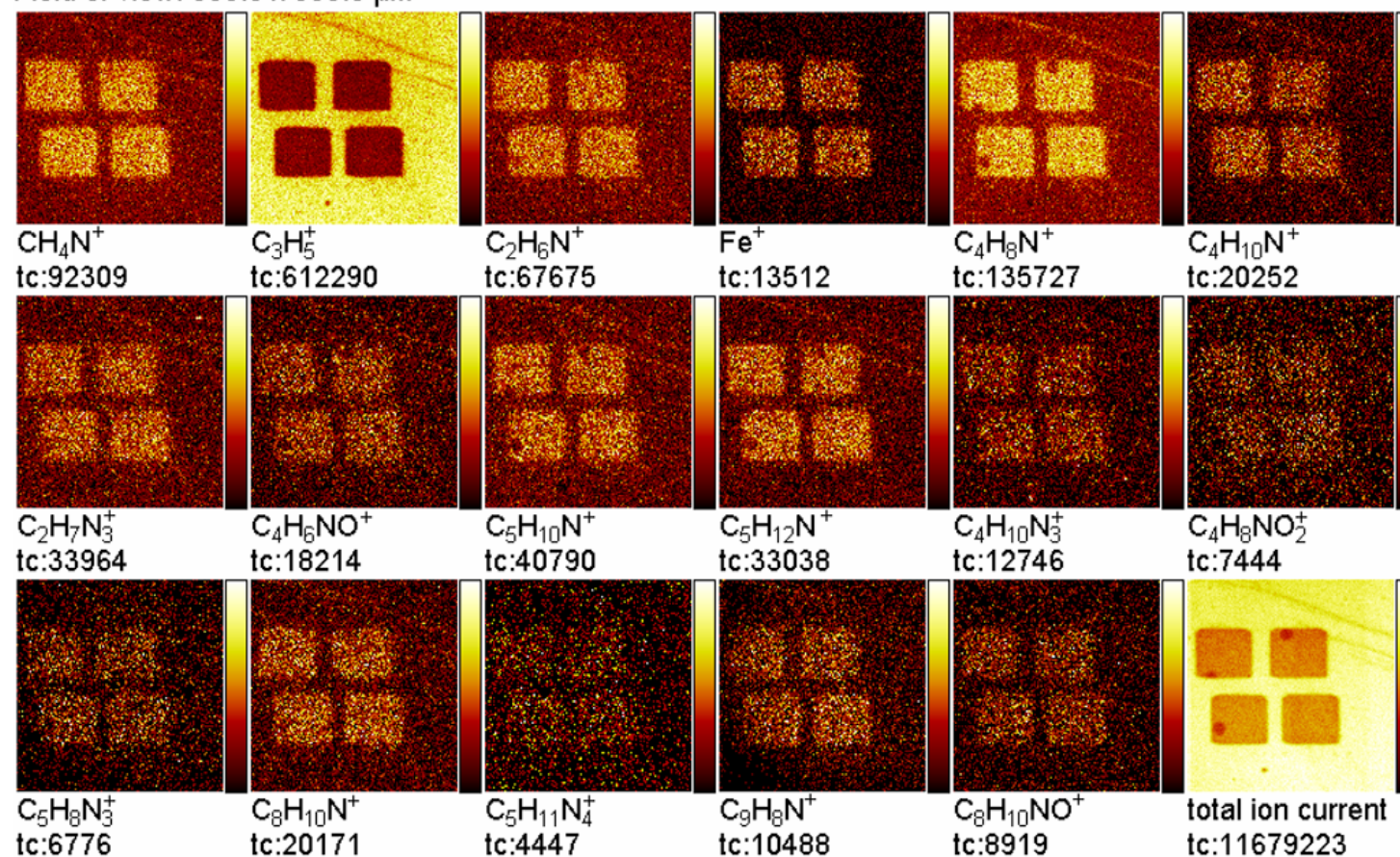


**Figure S1**

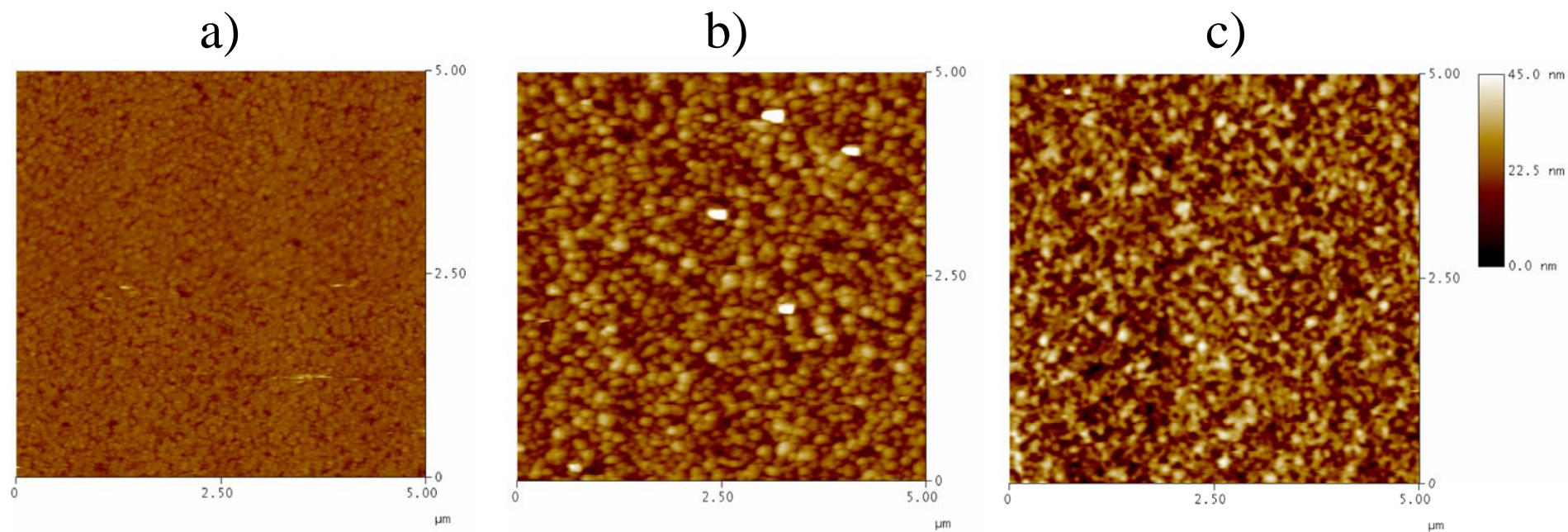
ToF-SIMS negative ion images of the pattern after the formation of the MB/MPTP SAM. A lighter colour in each mass resolved image indicates a higher intensity of the pertaining signal. The numbers reported below each image refer to the number of counts.

Figure clearly shows that the MPTP/MB SAM is confined in the etched regions of the pattern, as indicated by the intensity distribution of the  $\text{CN}^-$  fragment and of the (quasi)molecular ions from MB ( $\text{C}_6\text{H}_5\text{S}^-$ ), MPTP ( $\text{C}_{21}\text{H}_{14}\text{N}_3\text{S}^-$ ) and from the MB/MPTP gold-attached cluster ( $\text{C}_{27}\text{H}_{29}\text{S}_2\text{N}_3\text{Au}^-$ ). For more details on ToF-SIMS of the mixed component MB/MPTP SAM, see refs. 16a and 16b in the communication.

Field of view: 500.0 x 500.0  $\mu\text{m}^2$



**Fig.S2 Mass resolved positive ToF-SIMS imaging of the pattern after lactoferrin adsorption, reporting the intensity distribution of the most relevant peaks in the ToF-SIMS spectrum, including several fragments from lactoferrin.**



**Fig. S3 AFM height images from differently treated regions: a) MUO-covered Au surface before FIB etching; b) central region of a FIB etched area; c) central region of a FIB etched area, after all the steps leading to lactoferrin adsorption.**